

**Notice of References Cited**

Application/Control No.

09/671,567

Applicant(s)/Patent Under  
Reexamination  
HSIEH, MING-TSUN

Examiner

John M. Villecco

Art Unit

2612

Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-4,739,495 /	04-1988	Levine, Peter A.	348/247
	B	US-5,113,246 /	05-1992	Ninomiya et al.	348/247
	C	US-5,436,659 /	07-1995	Vincent, John A.	348/246
	D	US-6,070,233 /	05-2000	Whittaker, Bruce Ernest	711/144
	E	US-6,396,539 /	05-2002	Heller et al.	348/246
	F	US-4,805,023 /	02-1989	Younse et al.	348/247
	G	US-4,893,185 /	01-1990	Fukushima et al.	348/247
	H	US-6,509,927 /	01-2003	Prater et al.	348/246
	I	US-6,665,009 /	12-2003	Dong, Kimble	348/246
	J	US-6,134,143 /	10-2000	Norman, Robert D.	365/185.09
	K	US-5,499,114 /	03-1996	Compton, John T.	348/246
	L	US-6,642,961 /	11-2003	Hsieh, Ming-Tsun	348/247
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 60084646 A /	05-1985	Japan	KOSUGE et al.	G06F 12/00
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

Tle